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**1 An experimental comparison of range image segmentation algorithm**  
 Hoover, A.; Jean-Baptiste, G.; Jiang, X.; Flynn, P.J.; Bunke, H.; Goldgof, D.B.; Bowyer, K.; Eggert, D.W.; Fitzgibbon, A.; Fisher, R.B.;  
 Pattern Analysis and Machine Intelligence, IEEE Transactions on , Volume: 18 , Issue: 7 , July 1996  
 Pages:673 - 689

[\[Abstract\]](#)   [\[PDF Full-Text \(2068 KB\)\]](#)   IEEE JNL

**2 Modeling and calibration of a structured light scanner for 3-D robot vision**

Chen, C.; Kak, A.;  
 Robotics and Automation. Proceedings. 1987 IEEE International Conference on , Volume: 4 , Mar 1987  
 Pages:807 - 815

[\[Abstract\]](#)   [\[PDF Full-Text \(880 KB\)\]](#)   IEEE CNF

**3 Comparing curved-surface range image segmenters**

Powell, M.W.; Bowyer, K.W.; Xiaoyi Jiang; Bunke, H.;  
 Computer Vision, 1998. Sixth International Conference on , 4-7 Jan. 1998  
 Pages:286 - 291

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**4 Determination of the identity, position and orientation of the topmo object in a pile: Some further experiments**

Yang, H.; Kak, A.;  
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**5 Automatic relighting of overlapping textures of a 3D model**

*Beauchesne, E.; Sbastien, R.;*

Computer Vision and Pattern Recognition, 2003. Proceedings. 2003 IEEE Computer Society Conference on , Volume: 2 , 18-20 June 2003

Pages:II - 166-73 vol.2

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**6 Dual-beam structured-light scanning for 3-D object modeling**

*Park, J.; DeSouza, G.N.; Kak, A.C.;*

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**JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard1 **1×N fiber bundle scanning switch**

Ford, J.E.; DiGiovanni, D.J.;

Photonics Technology Letters, IEEE , Volume: 10 , Issue: 7 , July 1998

Pages:967 - 969

[\[Abstract\]](#)[\[PDF Full-Text \(208 KB\)\]](#)[IEEE JNL](#)

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**1 Self-oscillating evanescent microwave probes for nondestructive evaluations of materials**
*Tabib-Azar, M.; Tao Zhang; LeClair, S.R.;*

Instrumentation and Measurement, IEEE Transactions on , Volume: 51 , Issue 5 , Oct. 2002

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**2 A new technique for automated wafer inspection and classification particles and crystalline defects**
*Lie Dou; Broderick, M.-P.;*

Advanced Semiconductor Manufacturing Conference and Workshop, 1997.

IEEE /SEMI , 10-12 Sept. 1997

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**3 Detection of urban areas in multispectral data**
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Remote Sensing and Data Fusion over Urban Areas, IEEE/ISPRS Joint Workshop 2001 , 8-9 Nov. 2001

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*Ferrara, M.B.; Welch, K.A.; Clementi, L.D.; Hunt, J.D.; Wolter, S.D.; Bates, E*

Advanced Semiconductor Manufacturing Conference and Workshop, 1995. AS 95 Proceedings. IEEE/SEMI 1995 , 13-15 Nov. 1995

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